

Attorney Docket No. SEL 249

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

#3
JCS03 U.S. PRO
09/829114
04/09/01

In Re Application of:

Hajime KIMURA

Serial No.: Not Assigned

Filed: Herewith

Art Unit:

For: SEMICONDUCTOR DEVICE AND METHOD
OF DRIVING THE SAME

EL613563911
"Express Mail" Mailing Label No. _____

Date of Deposit April 9, 2001

I hereby certify that this correspondence is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service under 37 CF 31.10 on the date indicated above and is addressed to: Commissioner for Patents, Washington, D.C. 20231

Name. ARMAUDO CHUNG
(typed or printed)

Signature Armando Chung

INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner for Patents
Washington, D.C. 20231

Dear Sir:

Pursuant to 37 C.F.R. §1.97, as revised on February 4, 1992, 1135 OG 23-24, Applicant hereby calls the Examiner's attention to documents listed on the attached form, which documents may be material to the examination of this application. Copies of the references are enclosed herewith for the Examiner's consideration.

No inference should be drawn that the attached list sets forth a comprehensive investigation of the prior art, that any or all are pertinent to the invention, or that any apparatus disclosed is equivalent to the subject invention.

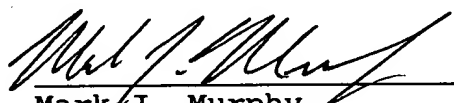
The citation of the above-discussed documents is not to be construed as an assertion that more pertinent art could not possibly be in existence. Citation of any document herein is not to be construed as an admission that any subject matter disclosed in the document is necessarily within the inventive field of

endeavor, that any disclosure is necessarily prior in time to a particular date which may be relevant to the instant patent application, and/or that any disclosure is otherwise necessarily prior art with respect to the instant invention.

Applicant also respectfully reserves the right to later set forth how the instant invention is distinguished over the disclosure of any document or other art, including the disclosure of those documents discussed herein, that may be cited by the Examiner in rejecting a claim in the instant patent application.

A first office action, notice of allowance or issue fee notification has not been received in this case, so Applicant does not believe that a fee is due. However, if any such fee is required, please charge our Deposit Account No. 50/1039.

Respectfully submitted,


Mark J. Murphy
Registration No.: 34,225

COOK, ALEX, McFARRON, MANZO,
CUMMINGS & MEHLER, LTD.
200 West Adams Street
Suite 2850
Chicago, Illinois 60606
(312) 236-8500

10903 U.S. PRO
09/829114
04/09/01

LIST OF PUBLICATIONS CITED BY APPLICANT	Attorney Docket No. SEL 249	Serial No. Not Assigned
	Applicant Hajime KIMURA	
	Filing Date Herewith	Group

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE

OTHER PUBLICATIONS
(Including Author, Title, Date, Pertinent Pages)

- | | |
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| | 1) Fossum, E.R., "CMOS Image Sensors: Electronic Camera on a Chip," IDEM 95, pp. 17-25, 1995.
2) Wong, H.S.P., "CMOS Image Sensors - Recent Advances and Device Scaling Considerations," IDEM 97, pp. 201-204, 1997.
3) Oba, E. et al, "A 1/2 Inch 330K Square Pixel Progressive Scan CMOS Active Pixel Image Sensor," 1997 IEEE International Solid State Circuits Conference, February 6-8, 1997, IEEE, vol. 40, pp. 180-181, 1997.
4) "Development Prospects of the CMOS Camera," JIEC Seminar, p. 9, Fig. 11, 1998.
5) Weisfield, R.L., "AmorphousSilicon TFT X-Ray Image Sensors," IEDM 98, pp. 21-24, 1998.
6) Moy, J.P et al, "X-Ray Detectors Based on Amorphous Silicon Active Matrix," EURODISPLAY '99, Proceedings of the 19th International Display Research Conference, Berlin, Germany, September 6-9, 1999, pp. 203-207.
7) Ikeda, M. et al, "Real-Time Imaging Flat Panel X-Ray Detector," AM-LCD '99, pp. 45-48, 1999. |
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EXAMINER:	DATE CONSIDERED:
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*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP form. Draw line through citation if not in conformance and not considered. Include a copy of this form with the next communication to applicant.